

Application/Control No.	Applicant(s)/Patent under Reexamination	
10/555,536	BOUAN, BRUNO	
Examiner	Art Unit	
Christopher Boswell	3676	

SEARCHED				
Class	Subclass	Date	Examiner	
70	57, 57.1, 58, 63	5/22/2007	СВ	
206	1.5, 307	5/22/2007	СВ	
	308.1			
	308.2			
	387.1			
	387.11			
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INTERFERENCE SEARCHED				
Class	Subclass	Date	Examiner	

SEARCH NOTES (INCLUDING SEARCH STRATEGY)			
	DATE	EXMR	
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